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Single-crystal growth and superconducting state of $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$

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Abstract

Single crystals of $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ were grown by a CsCl-flux method. Electrical resistivity $\rho(T)$ measurements were performed to reveal its superconducting properties. The $\rho(T)$ of the single crystal shows semiconducting-like behavior and superconducting transition at 3.4 K. The value is slightly higher than that of the polycrystalline sample with substitution amounts of $x = 0.2$ ($T_c \sim 2.5$ K). From $\rho(T)$ measurements in several magnetic fields, $\mu_0 H_{c2}^{//ab}(0)$ and $\mu_0 H_{c2}^{//c}(0)$ are estimated to be 17.2 T and 0.59 T, respectively. The superconducting anisotropic parameter γ is determined to be 29.2.

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1. Introduction

Since the discovery of superconductivity with superconducting transition temperature T_c at 8.6 K in the layered bismuth oxysulfide $\text{Bi}_4\text{O}_4\text{S}_3$ [1], other BiS₂-based superconductivity have been studied. LaOBiS_2 crystallizes with a space group $P4/nmm$ (No. 129) and this structure is composed of alternating superconducting BiS₂ layers and blocking LaO layers, which are similar to Fe-based superconductors. Substituting F for O induces superconductivity with $T_c = 2.5$ K [2], as well as tetravalent elements (Ti, Zr, Hf and Th) for La [3]. In addition, by replacing S atoms

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to Se atoms, T_c is enhanced: $T_c = 4.2$ K for $\text{LaO}_{0.5}\text{F}_{0.5}\text{BiSe}$ [4], 3.7 K for $\text{LaO}_{0.5}\text{F}_{0.5}\text{BiSe}_2$ [5]. The enhancement of T_c in Se doped compounds is induced by an in-plane chemical pressure [6].

In this article, we report the single crystal growth of $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ and its superconducting properties. In order to clarify superconducting state, we measured the electrical transport properties of $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ at low temperature and strong magnetic fields up to 11 T.

2. Experimental Details

Single crystals of $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ were grown by a CsCl-flux method similar to the previous reports [5,6]. The starting materials of 0.8 g and CsCl of 5 g were mixed and sealed in an evacuated quartz tube. The tube was heated up to 880 °C in 10 h and to 900 °C in 2 h, then kept for 10 h and cooled down to 650 °C for 125 h. The obtained materials were washed by water, ethanol, and acetone in order to remove the flux materials. The obtained single crystals were plate-like shape with approximately $1.0 \times 1.0 \text{ mm}^2$. The crystal structure of the single crystal was examined by an X-ray diffraction (XRD) method using a conventional X-ray spectrometer equipped with $\text{Cu-K}\alpha$ radiation and a monochromator (RAD-2X, Rigaku). Electrical resistivity $\rho(T)$ from 0.5 K to 300 K was measured under magnetic fields up to 11 T along the ab -plane and c -plane by dc-four-probe method in a ^3He cryostat (Oxford Heliox VL).

3. Experimental Result

3.1. X-ray diffraction

Figure 1 shows the XRD diffraction pattern of several single crystals $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ at room temperature. Only $(00l)$ diffraction peaks were observed, indicating the crystallographic c -axis is perpendicular to the crystal plane. All the reflections can be indexed as the space group of $P4/nmm$ and no extra peaks due to impurity phase can be detected from the XRD pattern. To estimate lattice constants, powder X-ray diffraction was performed by using powder crashed from single crystals. The lattice constants of $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ are obtained to be $a = 4.0856 \text{ \AA}$ and $c = 13.453 \text{ \AA}$. These values are slightly larger than those of the single crystal $\text{LaO}_{0.5}\text{F}_{0.5}\text{BiS}_2$, which suggest that S atoms are substituted with Se atoms.

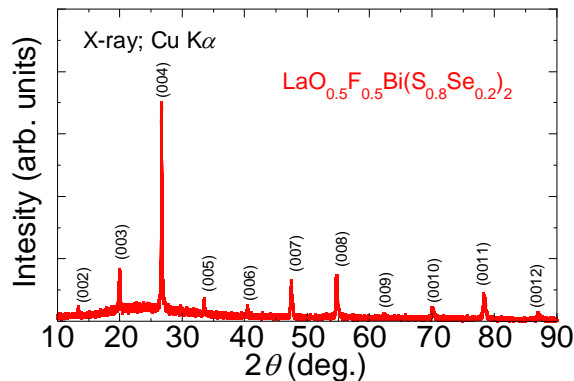


Fig. 1. XRD diffraction pattern of single crystals $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ at room temperature.

3-2. Electrical resistivity

Figure 2 shows temperature dependence of the electrical resistivity $\rho(T)$ of $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ down to 0.5 K with electrical current along the ab -plane. A semiconducting-like behavior was observed and superconducting transition was detected. T_c is defined as 50 % drop from residual resistivity ρ_0 and determined to be 3.4 K. ρ_0 is defined at just above T_c ($\rho_0 = 3.5 \text{ m}\Omega\text{cm}$). Compared with polycrystalline sample of $\text{LaO}_{0.5}\text{F}_{0.5}\text{Bi}(\text{S}_{0.8}\text{Se}_{0.2})_2$ [7],

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